

**METHOD AND APPARATUS FOR GENERATING VALUES FOR  
SELECTED PIXELS USED IN EVALUATING SEMICONDUCTOR  
WAFER BUMPS**

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**ABSTRACT**

Plural light sources are provided for directing ring patterns of light toward at least one reflective bump formed on and projecting from a first wafer surface of a semiconductor wafer. The intensity of light from the light sources may be varied and may be varied independently of one another. A method and apparatus for adjusting at least one pixel value is also disclosed.